

<b>Notice of References Cited</b>	Application/Control No. 10/723,178		Applicant(s)/Patent Under Reexamination NAM ET AL.	
	Examiner (Nancy) Thanh-Nhan P. Nguyen		Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2001/0026345	10-2001	Park et al.	349/149
*	B	US-2003/0218713	11-2003	Suzuki et al.	349/156
*	C	US-2005/0151920	07-2005	Watanabe et al.	349/153
*	D	US-6,771,348	08-2004	Oh et al.	349/152
*	E	US-2004/0125308	07-2004	Park et al.	349/149
*	F	US-2003/0117567	06-2003	Jung et al.	349/149
*	G	US-2003/0038913	02-2003	Choo, Kyo-Seop	349/149
*	H	US-2002/0051110	05-2002	Kim, Dong-Gyu	349/149
*	I	US-6,835,896	12-2004	Hwang et al.	174/255
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.